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CONFIRMATION NO. 2213

SERIAL NUMBER	FILING or 371(c) DATE	CLASS	GROUP ART UNIT	ATTORNEY DOCKET NO.		
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RULE						
APPLICANTS Fumi Nabeshima, Hiratsuka-shi, JAPAN; Kazuya Togashi, Hiratsuka-shi, JAPAN; Hiroshi Jiken, Hiratsuka-shi, JAPAN; Yoshinori Suenaga, Hiratsuka-shi, JAPAN;						
** CONTINUING DATA ***** This application is a CON of PCT/JP05/07120 04/13/2005						
** FOREIGN APPLICATIONS ***** JAPAN 2004-117910 04/13/2004						
** IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 06/21/2007						
Foreign Priority claimed <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No 35 USC 119(a-d) conditions met <input type="checkbox"/> Yes <input checked="" type="checkbox"/> No Verified and Acknowledged <u>/ROY M PUNNOOSE/</u> Examiner's Signature		<input type="checkbox"/> Met after Allowance Initials	STATE OR COUNTRY JAPAN	SHEETS DRAWINGS 6	TOTAL CLAIMS 6	INDEPENDENT CLAIMS 2
ADDRESS JOSEPH P. FARRAR 2-4-6 TSUKUDA SUITE 709 CHUO-KU, TOKYO, 104-0051 JAPAN						
TITLE Semiconductor wafer inspection device and method						
FILING FEE RECEIVED 1130	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:			<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		